

Application/Control No.	Applicant(s)/Patent under Reexamination LEEK, WILLIAM F.	
10/626,787		
Examiner	Art Unit	
Phi D. A	3637	

SEARCHED					
Class	Subclass	Date	Examiner		
74	441	7/11/2006	PA		
	409	i			
267	172				
	170				
52	295				
	293.3				
	296				
	223.1				
	223.13		Ψ		
	223.14				
	298				
	702				
<u></u>	714				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	1				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
search from parent case 09/729491 updated	7/11/2006				
Neil Wilson 411/231*, 432, 917* updated search from parent case	7/11/2006				
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